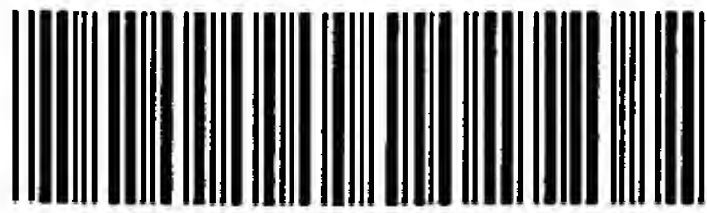


**Search Notes**



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**Examiner**

A. Sefer

**Applicant(s)/Patent under  
Reexamination**

CHUN ET AL.

**Art Unit**

2826

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search updated	9/18/2006	AS